

Notice of References Cited	Application/Control No. 10/828,319	Applicant(s)/Patent Under Reexamination SHARMA ET AL.	
	Examiner Leith A. Al-Nazer	Art Unit 2821	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0143720	06-2005	Yamada et al.	606/010
*	B	US-6,901,084	05-2005	Pask et al.	372/3
*	C	US-6,844,963	01-2005	Iketaki et al.	359/368
*	D	US-6,636,537	10-2003	Takada, Yasutoshi	372/23
*	E	US-5,815,518	09-1998	Reed et al.	372/6
*	F	US-5,796,761	08-1998	Injeyan et al.	372/3
*	G	US-2005/0163426	07-2005	Fermann et al.	385/037
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	DE 40 29 530 A1	03-1992	Germany	Steiger, Erwin	A61B 17/22
*	O	EP 1 241 746 A1	09-2002	Europe	Bonaccini et al.	H01S 3/094
*	P	EP 0 867 151 A2	09-1998	Europe	Omori et al.	A61B 17/36
*	Q	EP 0 867 151 A3	09-1998	Europe	Omori et al.	A61B 17/36
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.